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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Luetzen, et al. Docket No.: INF-115
Serial No: 10/721,225 Art Unit: 1765
Date Filed: November 26, 2003
Title: Method and Structures for Increasing the Structure Density and the Storage Capacitance in a Semiconductor Wafer

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Respectfully submitted,



Natalie Swider
Legal Assistant

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NUM333

0012

POWER OF ATTORNEY

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FOR PATENT APPLICATION

ATTORNEY DOCKET NO. INF-115

As a below named inventor for the PATENT APPLICATION entitled:

Method and Structures for Increasing the Structure Density and the Storage Capacitance in a Semiconductor Wafer

Application Serial No. 10/721,225, filed on November 26, 2003, I hereby appoint the following attorneys listed below to prosecute this application and transact all business in the Patent and Trademark Office connected therewith.

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December 24th, 2004

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